- Package Options Include Plastic "Small Outline" Packages, Ceramic Chip Carriers and Flat Packages, and Plastic and Ceramic DIPs
- Dependable Texas Instruments Quality and Reliability

description

These devices contain two independent $J-\overline{K}$ positive-edge-triggered flip-flops. A low level at the preset or clear inputs sets or resets the outputs regardless of the levels of the other inputs. When preset and clear are inactive (high), data at the J and \overline{K} inputs meeting the setup time requirements are transferred to the outputs on the positive-going edge of the clock pulse. Clock triggering occurs at a voltage level and is not directly related to the rise time of the clock pulse. Following the hold time interval, data at the J and \overline{K} inputs may be changed without affecting the levels at the outputs. These versatile flip-flops can perform as toggle flip-flops by grounding \overline{K} and tying J high. They also can perform as D-type flip-flops if J and \overline{K} are tied together.

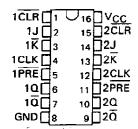
The SN54109 and SN54LS109A are characterized for operation over the full military temperature range of -55° C to 125 $^{\circ}$ C. The SN74109 and SN74LS109A are characterized for operation from 0 $^{\circ}$ C to 70 $^{\circ}$ C.

FUNCTION TABLE (each flip-flop)

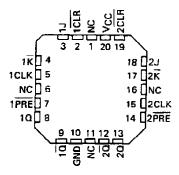
	IN	PUTS			OUT	PUTS
PRE	CLR	CLK	J	K	a	ā
L	Н	X	х	Х	H	L
H	L	×	X	X	L	н
L	L	X	Х	Х	Нţ	Н‡
Н	н	f	L	L	L	Н
н	Н	t	Н	L	TOGG	GLE
н	Н	Ť	Ł	н	0.0	₫₀
н	Н	t	Н	н	H	L
н	н	L	X	X	Q ₀	\overline{a}_0

 $^{^\}dagger$ The output levels in this configuration are not guaranteed to meet the minimum levels for V $_{OH}$ if the lows at preset and clear are near V $_{IL}$ maximum. Furthermore, this configuration is nonstable; that is, it will not persist when preset or clear return to their inactive (high) level.

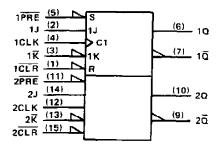
SN54109, SN54LS109A...J OR W PACKAGE SN74109...N PACKAGE SN74LS109A...D OR N PACKAGE (TOP VIEW)



SN54LS109A . . . FK PACKAGE (TOP VIEW)



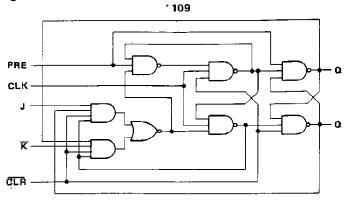
logic symbol‡



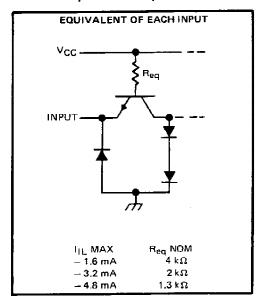
[‡]This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for D, J, N, and W packages.

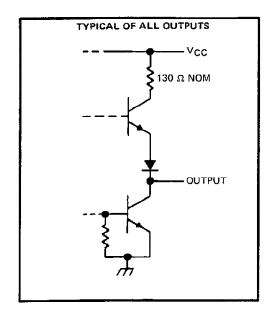
logic diagram (positive logic)

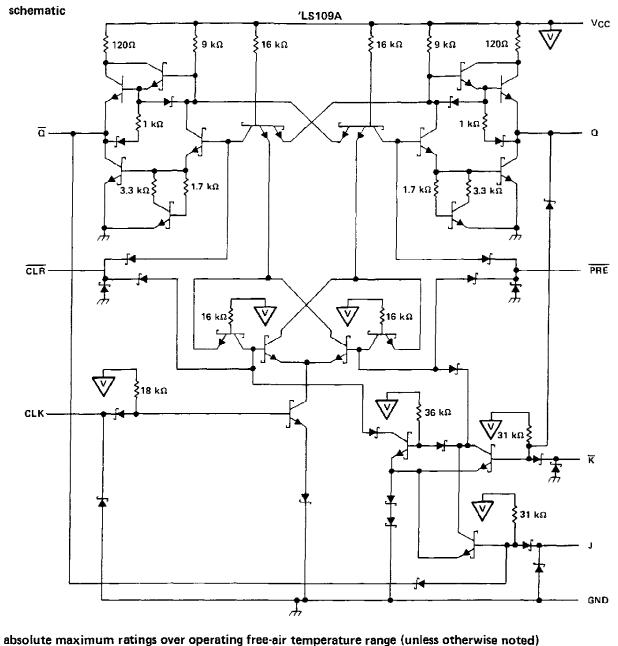


schematics of inputs and outputs



109





Supply voltage, VCC (see Note 1)	***************************************	7 V
Input voltage: '109	<u> </u>	5.5 V
'LS109A		
Operating free-air temperature range:	SN54'	- 55°C to 125°C
·	SN74'	0°C to 70°C
Storage temperature range	***************************************	- 65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.



SN54109, SN74109 DUAL J-K POSITIVE-EDGE-TRIGGERED FLIP-FLOPS WITH PRESET AND CLEAR

recommended operating conditions

				SN54109		SN74109			
			MIN	MOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage		4.5	5	5.5	4.75	5	5.25	V
VIH	High-level input voltage		2			2			V
٧ıL	Low-level input voltage			.,	8.0			0.8	V
ІОН	High-level output current				- 0.8			- 0.8	mΑ
IOL	Low-level output current				16			16	mA
	Pulse duration	CLK high or low	20			20			
t _W	Fuise duration	PRE or CLR low	20		"	20		T	nş
tsu	Input setup time before CLK 1		10			10			ns
th_	Input hold time-data after CLK1		6			6			ns
TΑ	Operating free-air temperature		~ 55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS†			SN5410	9	T	T			
1211	AIVIETEIS !		TEST CONSTIT		MIN	TYP‡	MAX	MIN	TYP‡	MAX	UNIT
Vικ		VCC = MIN,	= - 12 mA				- 1.5			- 1.5	V
VOH		V _{CC} = MIN, I _{OH} = - 0.8 mA	V _{IH} = 2 V,	V _{IL} ≈ 0.8 V,	2.4	3.4		2.4	3.4		V
VOL		V _{CC} = MIN, I _{OL} = 16 mA	V _{IH} = 2 V,	V _{IL} = 0.8 V,		0.2	0.4		0.2	0.4	٧
11		V _{CC} = MAX,	V _I = 5.5 V	<u> </u>			1		·	1	mA
	J or K						40			40	
ΉΗ	CLR	V _{CC} = MAX,	V. ~ 2.4 V				160			160	
'1H	PRE or CLK	¥((C 1417)),		1 2			80			80	μА
	Jor ₹		<u>-</u>				- 1.6			- 1.6	
1	CLR ¹	V+ MAY	V. = 0.4 V				- 4.8			- 4.8	mΑ
ΉL	PRE¶	V _{CC} = MAX,	V ₁ = 0.4 V				- 3.2			- 3.2	
	CLK		- ·				- 3.2			-3.2	
los§		V _{CC} = MAX			- 30		- 85	- 30		- 85	mA
ICC#		VCC = MAX,	See Note 2			9	15		9	15	mΑ

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

NOTE 2: With all outputs open. ICC is measured with the Q and Q outputs high in turn. At the time of measurement, the clock input is grounded,

switching characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$ (see note 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT		
fmax				25	33		MHz		
tPLH	PRE	O.			10	15	nş		
tPHL		ā			23	35	ns		
tPLH t		CLB	CLB	CLR	ব	$R_L = 400 \Omega$, $C_L = 15 pF$		10	15
tPHL		٩			17	25	ns		
₹₽LH	CLK	QorQ			10	16	ns		
^t PHL	CER	2312			18	28	ns		

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.



[‡] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25 \,^{\circ}\text{C}$.

⁵ Not more than one output should be shorted at a time.

¹ Clear is tested with preset high and preset is tested with clear high.

[#] Average per flip-flop.

SN54LS109A, SN74LS109A DUAL J-K POSITIVE-EDGE-TRIGGERED FLIP-FLOPS WITH PRESET AND CLEAR

recommended operating conditions

			SN54LS109A			SN74LS109A			ÚNIT
			MIN	MOM	MAX	MIN	NOM	MAX	UNIT
v _{CC}	Supply voltage		4.5	5	5.5	4.75	5	5.25	٧
VIH	High-level input voltage		2			2			V
VIL	Low-level input voltage				0.7			0.8	V
ТОН	High-level output current		T		- 0.4		••	- 0.4	mA
ТОЦ	Low-level output current				4			8	mA
fclock	Clock frequency		0		25	0		25	MHz
	Pulse duration	CLK high	25		_	25	_		
t₩	Pulse duration	PRE or CLR low	25			25			ns
	Beautiful before Cl K t	High-level data	35			35			
t _{su}	Setup time before CLK 1	Low-level data	25			25			ns
th .	Hold time-data after CLK↑		5			5			ns
TA	Operating free-air temperature		- 55		125	0		70	°c

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS†			SN54LS109A				SN74LS109A			
FARAINETER	1	SI COMBILIONS.		MIN	TYP#	MAX	MIN	TYP‡	MAX	דומט	
Vik	VCC - MIN,	I _I = - 18 mA				– 1.5		_	1.5	V	
VOH	V _{CC} = MIN, I _{OH} = - 0.4 mA	V _{IH} = 2 V, V _{IL}	= MAX,	2.5	3.4		2.7	3.4		٧	
V	V _{CC} = MIN, I _{OL} = 4 mA	VIL = MAX, VIL	= 2 V,		0.25	0,4		0.25	0.4	v	
VOL	V _{CC} = MIN, I _{OL} = 8 mA	VIL = MAX, VII	_i = 2 V,					0.35	0.5	ľ	
J, K or CLK	Vcc = MAX,	V ₁ = 7 V				0.1			0.1	mA	
CLR or PRE	VCC - MAX,	41-74				0.2			0.2	П	
J, R or CLK	V _{CC} = MAX,	V ₁ = 2.7 V				20			20		
CLR or PRE	7 700 - 14100	V - 2,7 V				40			40	μА	
J, K or CLK	V _{CC} = MAX,					- 0.4			- 0.4	^	
CLR or PRE	ACC - MWY	V _I = 0.4 V	*		- 0.8		- 0.8		- 0.8	- mA	
OS§	VCC = MAX,	See Note 4		- 20	_	100	- 20		100	mA	
I _{CC} (Total)	V _{CC} = MAX,	See Note 2		- · - ·	4	8		4	8	mA	

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions,

NOTE 2: With all outputs open, ICC is measured with the Q and Q outputs high in turn. At the time of measurement, the clock input is grounded.

NOTE 4: For certain devices where state commutation can be caused by shorting an output to ground, an equivalent test may be performed with V_O = 2.25 V and 2.125 V for the 54 family and the 74 family, respectively with the minimum and maximum limits reduced to one half of their stated values.

switching characteristics, V_{CC} = 5 V, T_A = 25°C (see note 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
f _{max}				25	33		MHz
^t PLH	CLR, PRE	Q or Q	$R_{\perp} = 2 k\Omega$, $C_{\perp} = 15 pF$		13	25	ns
tPHL_	or CLK				25	40	ns

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.



[‡] All typical values are at V_{CC} = 5 V, T_A = 25°C. §Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second.

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